

# Trace norm and trace distance

## Definition (Trace norm)

The *trace norm* of a linear operator  $X \in \mathcal{L}(\mathcal{H})$  is

$$\|X\|_1 = \operatorname{tr}\sqrt{X^\dagger X} = \sum_{i=1}^d s_i(X),$$

where  $d = \dim\mathcal{H}$  and  $s_i(X)$  are the singular values of  $X$ .

## Trace distance

The *trace distance* of quantum states  $\rho$  and  $\sigma$  is defined as

$$D(\rho, \sigma) := \frac{1}{2} \|\rho - \sigma\|_1.$$

## Fidelity

The *fidelity*  $F(\rho, \sigma)$  of quantum states  $\rho$  and  $\sigma$  is defined as

$$F(\rho, \sigma) = \left\| \sqrt{\rho} \sqrt{\sigma} \right\|_1 = \operatorname{tr}(\sigma^{1/2} \rho \sigma^{1/2})^{1/2}.$$

## Properties of trace distance and fidelity

- (i)  $D(\cdot, \cdot)$  is a **metric** (non-negative, symmetric and satisfying triangle inequality), but fidelity is not. We do have  $F(\rho, \sigma) = F(\sigma, \rho) \geq 0$ .
- (ii)  $0 \leq D(\rho, \sigma) \leq 1$  and  $D(\rho, \sigma) = 0$  iff  $\rho = \sigma$ , while  $D(\rho, \sigma) = 1$  iff  $\text{supp}(\rho) \perp \text{supp}(\sigma)$ .  
 $0 \leq F(\rho, \sigma) \leq 1$  and  $F(\rho, \sigma) = 1$  iff  $\rho = \sigma$ , while  $F(\rho, \sigma) = 0$  iff  $\text{supp}(\rho) \perp \text{supp}(\sigma)$ .
- (iii)  $D(\rho, \sigma) = \sup\{\text{tr}[P(\rho - \sigma)] : P \geq 0 \text{ and } \mathbb{1} - P \geq 0\}$ .
- (iv) **Data-processing:**

$D(\rho, \sigma) = D(U\rho U^\dagger, U\sigma U^\dagger)$  and  $F(\rho, \sigma) = F(U\rho U^\dagger, U\sigma U^\dagger)$  for all unitaries  $U$ ;

$D(\rho_A, \sigma_A) \leq D(\rho_{AB}, \sigma_{AB})$  and  $F(\rho_{AB}, \sigma_{AB}) \leq F(\rho_A, \sigma_A)$ .

- (v) Let  $\rho_i, \sigma_i$  be quantum states and  $(p_i)_i$  a probability distribution.  
 $D(\cdot, \cdot)$  is **jointly convex**,

$$D\left(\sum_i p_i \rho_i, \sum_i p_i \sigma_i\right) \leq \sum_i p_i D(\rho_i, \sigma_i),$$

while  $F(\cdot, \cdot)$  is **jointly concave**,

$$F\left(\sum_i p_i \rho_i, \sum_i p_i \sigma_i\right) \geq \sum_i p_i F(\rho_i, \sigma_i).$$

## Properties of trace distance and fidelity

- (i) **Holevo-Helstrom theorem:**  $D(\rho, \sigma)$  is related to the maximum success probability  $p_{\text{succ}}(\rho, \sigma)$  of distinguishing between  $\rho$  and  $\sigma$ ,

$$p_{\text{succ}}(\rho, \sigma) = \frac{1}{2} (1 + D(\rho, \sigma)).$$

- (ii) **Uhlmann's theorem:**

$$F(\rho, \sigma) = \max\{|\langle \psi^\rho | \phi^\sigma \rangle|\}$$

where the maximization is over purifications  $|\psi^\rho\rangle, |\phi^\sigma\rangle$  of  $\rho, \sigma$ , respectively.

- (iii) **Fuchs-van-de-Graaf inequalities:**

$$1 - F(\rho, \sigma) \leq D(\rho, \sigma) \leq \sqrt{1 - F(\rho, \sigma)^2}.$$